

P-2.1 Subcommittee on Ceramic Dielectric Capacitors

AGENDA Wednesday, September 29, 2010 Sheraton Austin Hotel at the Capitol Austin, TX

1.0 Introductions

1.1 Circulate Membership Roster

1.2 Approval of Spring 2010 Meeting Minutes from Orlando, FL

1.3 Approval of Agenda for Present Meeting

1.4 Correspondence & Review of Committee's Scope

1.5 Report of task groups and committees

2.0 Old Business

2.1 Status of EIA-198-F "Ceramic Dielectric Capacitors Classes I, II, III, & IV"

2.1.1 Part III/3- standard two-terminal SMD (PN 5099)

2.1.2 Part III/6- Axial PTH (PN 5154), publish status

2.1.2.1 Part III/9- High voltage PTH & SMD, dimensions/TCVC

2.1.2.2 Part III/10- Multi-terminal SMD

2.2 Ballot status on high frequency test method of low inductance MLCCs (PN 4563)

2.3 Revision status of ANSI/EIA 521 (PN 5095)

2.4 Five-year review of documents

2.4.1 EIA 198, Section 2, Test Methods

2.4.2 EIA 198, Section 3, Individual Specifications

3.0 New Business

3.1 EIA 469 Destructive Physical Analysis Test Method, PN status

4.0 Time and Place of next meeting

5.0 Adjournment